

PATENT
450104-05892

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Mitsuhiro SHIKIDA et al.
International Application No.: PCT/JP2005/000633
International Filing Date: January 13, 2005
For: CHEMICAL ANALYTIC APPARATUS AND
CHEMICAL ANALYTIC METHOD

745 Fifth Avenue
New York, NY 10151

EXPRESS MAIL

Mailing Label Number: EV195879488US

Date of Deposit: July 14, 2006

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" Service under 37 CFR 1.10 on the date indicated above and is addressed to Mail Stop PCT, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Barnet Shindler
(Typed or printed name of person mailing paper or fee)

Barnet Shindler
(Signature of person mailing paper or fee)

INFORMATION DISCLOSURE STATEMENT

Mail Stop PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP2005/000633. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

PATENT
450104-05892


REMARKS

Entry of this Information Disclosure Statement and an early examination on the merits
are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
Attorneys for Applicants

By: 
William S. Frommer
Reg. No. 25,506
Tel. (212) 588-0800

Enclosures

AP20 Rec'd PCT/PTO 14 JUL 2006

Sheet 1 of 1

Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 450104-05892		10/586165 INT'L APPL. NO. PCT/JP2005/000635
	APPLICANT Mitsuhiro SHIKIDA et al.		
	LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	INT'L FILING DATE January 13, 2005	GROUP Unknown

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	2004 0134854	07/15/04	Higuchi et al.			
	AB	2003 0026705	02/06/03	Ishiguro et al.			
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AF	WO 02 066992	08/29/02	PCT			
	AG	EP 1 371 989	12/17/03	Europe			
	AH	2003 50245	02/21/03	Japan			
	AI	EP 1 270 066	01/02/03	Europe			
	AJ	WO 03 026798	04/03/03	PCT			
	AK	2005 503572	02/03/05	Japan			
	AL	2003 169661	06/17/03	Japan			
	AM	WO 02 087764	11/07/02	PCT			
	AN	2004 535916	12/02/04	Japan			
	AO	8 178931	07/12/96	Japan			
	AP						
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ						
	AR						
	AS						
EXAMINER				DATE CONSIDERED			
<p>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							